

EUV photodiode

General Features:

- SiC-based extreme ultraviolet (EUV) photodiode
- Excellent stability under high fluence EUV exposure
- Photovoltaic mode operation
- Visible blind and low dark current
- High detection efficiency for 13.5 nm EUV radiation
- Ceramic package

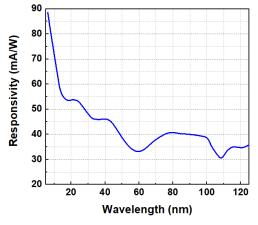
Applications: EUV radiation monitoring and flux measurement

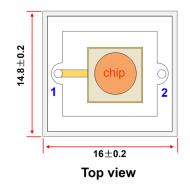
Specifications:

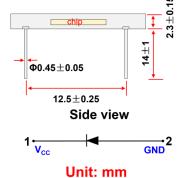
Parameters	Symbol	Value	Unit
Maximum ratings			
Operation temperature range	T _{opt}	-20-80	°C
Storage temperature range	T _{sto}	-55-90	°C
Soldering temperature (3 s)	T _{sol}	260	°C
Maxium reverse voltage	$V_{r\text{-max}}$	-20	V
Electro-Optical characteristics (25 °C)			
Chip size	Α	19.6	mm²
Spectral response range	λ	5-125	nm
Responsivity (@ 13.5 nm)	R	58	mA/W
Dark current (V _r = -1V)	I _d	< 100	рА
Shunt resistance (@±10mV)	R _{sh}	>10	GΩ
Capacitance (@ 0 V and 1 MHz)	Cp	565	pF
Rise Time (V_r =0 V , R_L =50 Ω)	t _r	< 1	μS

Spectral response

Package dimensions (unit: mm)







Model: SCT-EUV20

Manufactured by GaNo Optoelectronics Inc. Suzhou, China